### **Ordering Information**

Part Number	Option RoHS Compliant	Package	Surface Mount	Tape and Reel	UL 1577	IEC 60747-5-5	Quantity
ACNT-H50L	-000E	15-mm	х		х	Х	80 per tube
	-500E	Stretched SO8	Х	Х	Х	Х	1000 per reel

ACNT-H50L is UL Recognized with 7500V<sub>RMS</sub> for 1 minute per UL1577.

To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry.

## Package Outline Drawing

#### ACNT-H50L Stretched SO8 Package



# Solder Reflow Profile

Recommended reflow conditions are as per JEDEC Standard, J-STD-020 (latest revision). Non-Halide Flux should be used.

## **Regulatory Information**

The ACNT-H50L is approved by the following organizations:

- UL: Approval under UL 1577, component recognition program up to V<sub>ISO</sub> = 7500V<sub>RMS</sub> File E55361.
- CSA: Approval under CSA Component Acceptance Notice #5, File CA 88324.
- IEC 60747-5-5: Maximum Working Insulation Voltage V<sub>IORM</sub> = 2262 V<sub>PEAK</sub>

## **Insulation and Safety Related Specifications**

Parameter	Symbol	ACNT-H50L	Unit	Conditions
Minimum External Air Gap (External Clearance)	L(101)	14.2	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (External Creepage)	L(102)	15	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)		0.5	mm	Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector.
Tracking Resistance (Comparative Tracking Index)	CTI	>300	V	DIN IEC 112/VDE 0303 Part 1
Isolation Group		Illa		Material Group (DIN VDE 0110, 1/89, Table 1)

# IEC 60747-5-5 Insulation Characteristics<sup>a</sup>

Description	Symbol	Characteristic	Unit
Installation Classification per DIN VDE 0110/39, Table 1			
for rated mains voltage $\leq$ 600V <sub>RMS</sub>		I – IV	
for rated mains voltage $\leq$ 1000V <sub>RMS</sub>		I – IV	
Climatic Classification		40/105/21	
Pollution Degree (DIN VDE 0110/39)		2	
Maximum Working Insulation Voltage	V <sub>IORM</sub>	2262	V <sub>peak</sub>
Input to Output Test Voltage, Method $b^a$ V <sub>IORM</sub> x 1.875 = V <sub>PR</sub> , 100% Production Test with t <sub>m</sub> = 1 sec, Partial Discharge < 5 pC	V <sub>PR</sub>	4241	V <sub>peak</sub>
Input to Output Test Voltage, Method a <sup>a</sup> V <sub>IORM</sub> x 1.6 = V <sub>PR</sub> , Type and Sample Test, t <sub>m</sub> = 10 sec, Partial Discharge < 5 pC	V <sub>PR</sub>	3619	V <sub>peak</sub>
Highest Allowable Overvoltage (Transient Overvoltage t <sub>ini</sub> = 60 sec)	V <sub>IOTM</sub>	12000	V <sub>peak</sub>
Safety-limiting values – Maximum Values Allowed in the Event of a Failure			
Case Temperature	Τ <sub>S</sub>	150	°C
Input Current	I <sub>S, INPUT</sub>	230	mA
Output Power	Ps, OUTPUT	1000	mW
Insulation Resistance at T <sub>S</sub> , V <sub>IO</sub> = 500V	R <sub>S</sub>	>10 <sup>9</sup>	Ω

a. Refer to the optocoupler section of the Isolation and Control Components Designer's Catalog, under Product Safety Regulations section, (IEC 60747-5-5) for a detailed description of Method a and Method b partial discharge test profiles.

## **Absolute Maximum Ratings**

Parameter	Symbol	Min.	Max.	Unit		
Storage Temperature	Τ <sub>S</sub>	-55	125	°C		
Operating Temperature	T <sub>A</sub>	-40	105	°C		
Average Forward Input Current	I <sub>F(avg)</sub>	—	20	mA		
Peak Forward Input Current (<1 μs Pulse Width, <10% Duty Cycle)	I <sub>F(peak)</sub>		80	mA		
Peak Transient Input Current (≤1 μs pulse width, <300 ps)	I <sub>F(trans)</sub>		1	A		
Reversed Input Voltage	V <sub>R</sub>	—	5	V		
Input Power Dissipation	P <sub>IN</sub>	—	35	mW		
Output Power Dissipation	Po	—	100	mW		
Average Output Current	I <sub>O(AVG)</sub>	—	8	mA		
Peak Output Current	I <sub>O(PEAK)</sub>	—	16	mA		
Supply Voltage	V <sub>CC</sub>	-0.5	30	V		
Output Voltage	Vo	-0.5	24	V		
Lead Solder Temperature	T <sub>LS</sub>	260°C for 10 sec, 1.6 mm below seating plane				
Solder Reflow Temperature Profile		Refer to Solder Reflow Profile section.				

## **Recommended Operating Conditions**

Parameter	Symbol	Min.	Max.	Unit
Supply Voltage	V <sub>CC</sub>	3.0	24	V
Input Current, High Level	I <sub>FH</sub>	10	18	mA
Operating Temperature	T <sub>A</sub>	-40	105	°C
Forward Input Voltage (OFF)	V <sub>F(OFF)</sub>	_	0.8	V

## **Electrical Specifications (DC)**

Over recommended operating  $T_A = -40^{\circ}$ C to +105°C, supply voltage (3.0V  $\leq V_{CC} \leq 24$ V) and unless otherwise specified. All typical values are at  $T_A = 25^{\circ}$ C.

Parameter	Symbol	Min.	Тур.	Max.	Unit		Conditions	;	Figure
Current Transfer Ratio	CTR <sup>a</sup>	31	50	80	%	T <sub>A</sub> = 25°C	V <sub>O</sub> = 0.4V	V <sub>CC</sub> = 3.3V or 5V I <sub>F</sub> = 12 mA	Figure 2, Figure 3
		21	_		%		V <sub>O</sub> = 0.5V		
Logic Low Output Voltage	V <sub>OL</sub>	—	0.2	0.4	V	T <sub>A</sub> = 25°C	I <sub>O</sub> = 3 mA	$V_{CC}$ = 3.3V or 5V	
		_	0.2	0.5	V		I <sub>O</sub> = 1.6 mA	I <sub>F</sub> = 12 mA	

Parameter	Symbol	Min.	Тур.	Max.	Unit		Conditions		Figure
Logic High Output Current	I <sub>ОН</sub>		0.014	0.5	μA	T <sub>A</sub> = 25°C	V <sub>O</sub> = V <sub>CC</sub> = 5.5V	I <sub>F</sub> = 0 mA	Figure 4, Figure 5
			0.06	1			$V_0 = V_{CC} =$ 24V		
				80			$V_0 = V_{CC} =$ 24V		
Logic Low Supply Current	ICCL		200	400	μΑ		I <sub>F</sub> = 12 mA, V <sub>O</sub> = open, V <sub>CC</sub> = 24V		
Logic High Supply Current	I <sub>ССН</sub>	_	_	2	μA		I <sub>F</sub> = 0 mA, V <sub>O</sub> = open, V <sub>CC</sub> = 24V		
Input Forward Voltage	V <sub>F</sub>	1.10	1.45	1.70	V		I <sub>F</sub> = 12 mA		Figure 1
Input Reversed Breakdown Voltage	BV <sub>R</sub>	7		_	V		I <sub>R</sub> =10 μA		
Temperature Coefficient of Forward Voltage	$\Delta V_F / \Delta T_A$	_	-1.5	_	mV/°C		I <sub>F</sub> =12 mA		
Input Capacitance	C <sub>IN</sub>		20	—	pF		f = 1 MHz, V <sub>F</sub> = 0		

a. Current Transfer Ratio in percent is defined as the ratio of output collector current,  $I_O$ , to the forward LED input current,  $I_F$ , times 100%.

# **Switching Specifications**

Over recommended operating (T<sub>A</sub> = –40°C to +105°C), I<sub>F</sub> = 12 mA, (3.0V  $\leq$  V<sub>CC</sub>  $\leq$  24V), unless otherwise specified.

Parameter	Symbol	Min.	Тур.	Max.	Unit		Test Conditions	Figure
Propagation Delay Time	T <sub>PHL</sub>	_	0.1	0.8	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle =	Figure 15
to Logic Low at Output		—		1.0	μs		50%, V <sub>CC</sub> = 3.3V, RL= 1.0 kΩ, CL = 15 pF, V <sub>THHL</sub> = 1.5V	Figure 6, Figure 15
		—	0.1	0.8	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle =	Figure 15
		—		1.0	μs		50%, V <sub>CC</sub> = 5.0V, R <sub>L</sub> = 1.6 kΩ, C <sub>L</sub> = 15 pF, V <sub>THHL</sub> = 1.5V	Figure 7, Figure 15
		—	0.15	0.8	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle =	Figure 15
		—		1.0	μs		50%, V <sub>CC</sub> = 24V, R <sub>L</sub> = 8.2 kΩ, C <sub>L</sub> = 15 pF, V <sub>THHL</sub> = 1.5V	Figure 8, Figure 15
Propagation Delay Time	T <sub>PLH</sub>	—	0.4	1.0	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle =	Figure 15
to Logic High at Output		—		1.3	μs		50%, V <sub>CC</sub> = 3.3V, R <sub>L</sub> = 1.0 kΩ, C <sub>L</sub> = 15 pF V <sub>THLH</sub> = 2.0V	Figure 6, Figure 15
		—	0.4	1.0	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle =	Figure 15
				1.3	μs		50%, V <sub>CC</sub> = 5.0V, R <sub>L</sub> = 1.6 kΩ, C <sub>L</sub> = 15 pF, V <sub>THLH</sub> = 2.0V	Figure 7, Figure 15
		_	0.4	1.0	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle =	Figure 15
		—		1.3	μs		50%, V <sub>CC</sub> = 24V, R <sub>L</sub> = 8.2 kΩ, C <sub>L</sub> = 15 pF, V <sub>THLH</sub> = 2.0V	Figure 8, Figure 15

Parameter	Symbol	Min.	Тур.	Max.	Unit		Test Conditions	Figure
Propagation Delay Difference Between Any			0.4	0.8	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle = $50\%$ , V <sub>CC</sub> = 3.3V, R <sub>L</sub> = 1.0 k $\Omega$ , C <sub>L</sub> =	
Two Parts <sup>a</sup>							15 pF, V <sub>THHL</sub> = 1.5V, V <sub>THLH</sub> = 2.0V	
		_	0.3	0.6	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle = 50%, $V_{CC}$ = 5.0V, $R_L$ = 1.6 kΩ, $C_L$ = 15 pF, $V_{THHL}$ = 1.5V, $V_{THLH}$ = 2.0V	
		_	0.3	0.6	μs	T <sub>A</sub> = 25°C	Pulse: f = 10 kHz, Duty cycle = 50%, V <sub>CC</sub> = 24V, R <sub>L</sub> = 8.2 k $\Omega$ , C <sub>L</sub> = 15 pF, V <sub>THHL</sub> = 1.5V, V <sub>THLH</sub> = 2.0V	
Common-Mode Transient Immunity at Logic High Output <sup>b</sup>	CM <sub>H</sub>	15	40	_	kV/μs	T <sub>A</sub> = 25°C	V <sub>CM</sub> = 1500V, I <sub>F</sub> = 0 mA, R <sub>L</sub> = 1.0 kΩ or 1.6 kΩ, V <sub>CC</sub> = 3.3V/5V	Figure 16
Common-Mode Transient Immunity at	CM <sub>L</sub>	15	40	—	kV/μs	T <sub>A</sub> = 25°C	$V_{CM}$ = 1500V, I <sub>F</sub> = 12 mA, R <sub>L</sub> = 1.6 kΩ, V <sub>CC</sub> = 5V	Figure 16
Logic Low Output <sup>c</sup>		15	40	_	kV/μs	T <sub>A</sub> = 25°C	$V_{CM}$ = 1500V, I <sub>F</sub> = 12 mA, R <sub>L</sub> = 1.0 kΩ, V <sub>CC</sub> = 3.3V	Figure 16

a. The difference between  $t_{\mathsf{PLH}}$  and  $t_{\mathsf{PHL}}$  between any two parts under the same test condition.

b. Common transient immunity in a Logic High level is the maximum tolerable (positive) dV<sub>CM</sub>/dt on the rising edge of the common-mode pulse, V<sub>CM</sub>, to assure that the output remains in a Logic High state.

c. Common-mode transient immunity in a Logic Low level is the maximum tolerable (negative) dV<sub>CM</sub>/dt on the falling edge of the common-mode pulse signal, V<sub>CM</sub> to assure that the output remains in a Logic Low state.

### **Package Characteristics**

All Typical at  $T_A = 25^{\circ}C$ .

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions
Input-Output Momentary	V <sub>ISO</sub>	7500	_	—	V <sub>rms</sub>	RH ≤ 50%, t = 1 min.,
Withstand Voltage <sup>a</sup>						T <sub>A</sub> = 25°C
Input-Output Resistance <sup>a</sup>	R <sub>I-O</sub>		10 <sup>14</sup>		Ω	V <sub>I-O</sub> = 500V DC
Input-Output Capacitance <sup>a</sup>	C <sub>I-O</sub>	_	0.6		pF	f = 1 MHz, T <sub>A</sub> = 25°C

a. Device considered a two terminal device: pins 2 and 3 shorted together and pins 5, 6, and 8 shorted together.

Figure 1: Input Current vs. Forward Voltage



Figure 3: Typical Current Transfer Ratio vs. Temperature



Figure 5: Typical Logic High Output Current vs. Temperature



Figure 2: Typical Current Transfer Ratio vs. Temperature







Figure 6: Typical Propagation Delay vs. Temperature



#### Figure 7: Typical Propagation Delay vs. Temperature



Figure 9: Typical Propagation Delay vs. Load Resistance



Figure 11: Typical Propagation Delay vs. Supply Voltage



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#### Figure 8: Typical Propagation Delay vs. Temperature







Figure 12: Typical Propagation Delay vs. Input Current





#### Figure 14: DC Pulse Transfer Characteristic



### **Test Circuits**

Figure 15: Switching Test Circuits



#### Figure 16: Test Circuit for Transient Immunity and Typical Waveforms



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